Application/Control No. Applicant(s)/Patent Under Reexamination 09/829,876 KIKUCHI ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Douglas W Owens 2811

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
	Ε	U\$-			
	F	US-			
	G	US-			
	Н	US-			
	. 1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
-	N					
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	Р					
	Q					
	R					
	S					
	Т	,				

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Stephen A. Campbell, The Science and Engineering of Microelectronic Fabrication, 1996, Oxford University Press, Inc., pp 49-50				
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	w					
	х					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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